

Title:	Performance report for SiT3372, 81.802971 MHz, HCSL		
Type:	Performance report	Rev:	1.2
Orig:		Date:	September 07, 2018

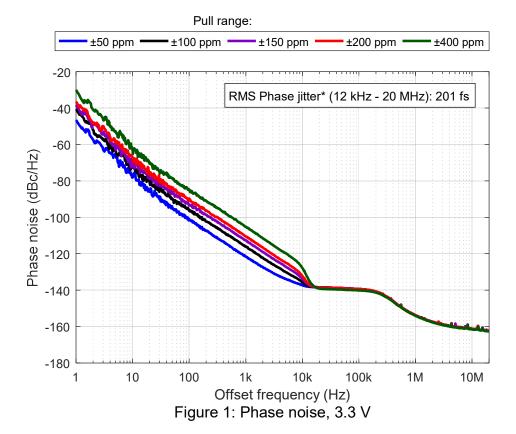
## Performance report for SiT3372 - 81.802971 MHz, HCSL

## This performance report contains the following data:

- Phase noise
- Random phase jitter
- Output waveforms
- Pull range linearity
- Frequency stability over temperature
- Period jitter
- Duty cycle
- Rise/Fall time
- Amplitude
- Current consumption



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\*Integrated phase jitter value applies for ±50 ppm to ±400 ppm pull ranges

Table 1: Phase noise

Phase noise dBc/Hz					
Frequency offset	Pull range (ppm)				
(Hz)	±50	±100	±150	±200	±400
1	-46.5	-40.6	-38.3	-36.4	-30.0
10	-76.5	-72.4	-72.1	-67.5	-63.8
100	-100.9	-95.9	-93.1	-89.6	-84.6
1 K	-121.6	-116.1	-112.5	-110.6	-105.2
10 K	-137.3	-135.7	-133.9	-132.2	-127.8
100 K	-139.5	-139.4	-139.4	-139.4	-140.2
1 M	-153.8	-153.9	-153.8	-153.8	-154.1
10 M	-161.3	-161.3	-161.3	-161.3	-161.6
20 M	-162.2	-162.3	-162.2	-162.3	-162.6

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Page 2 of 10



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Table 2: Integrated Phase jitter

Parameter	Units	Pull range (ppm)	
Parameter	Utills	±50 to ±400	
Integrated Phase jitter (1.875 MHz - 20 MHz)	fs, rms	106	
Integrated Phase jitter (12 kHz - 20 MHz)	fs, rms	201	



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Figure 2: Output waveform, 2.5 V



Figure 3: Output waveform, 3.3 V

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Page 4 of 10



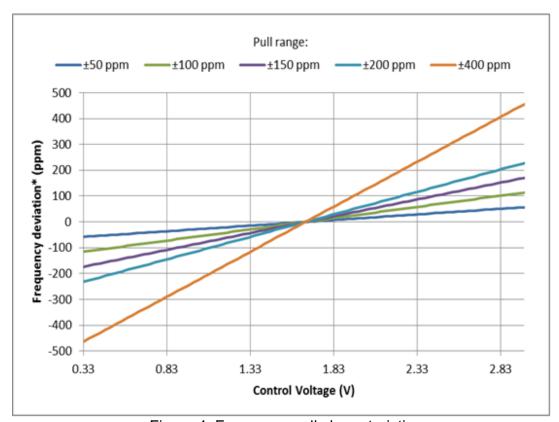


Figure 4: Frequency pull characteristic



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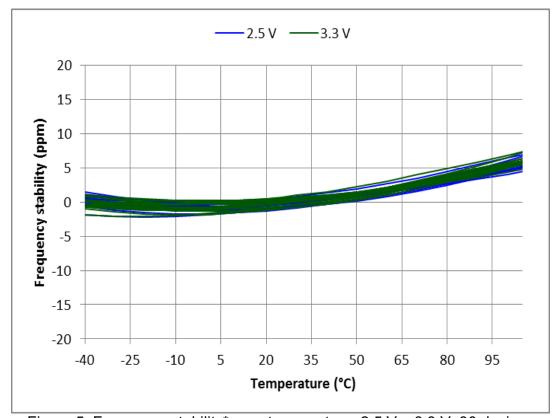


Figure 5: Frequency stability\* over temperature, 2.5 V – 3.3 V, 30 devices

\*SiT3372 frequency stability is independent of output frequency.



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Table 3: Summary performance data

Parameter	Units	Voltage		
Parameter	UTILS	2.5 V	3.3 V	
Period jitter	ps, rms	1.00	0.99	
Period jitter (sample size 10,000 cycles)	ps, pk-pk	7.67	7.64	
Duty cycle	%	50.0	50.0	
Rise time (20% - 80%)	ps	368	366	
Fall time (80% - 20%)	ps	367	365	
Differential voltage swing	V	1.38	1.45	
Current consumption (no load, output enabled)	mA	81.9	82.4	
Current consumption (no load, output disabled)	mA	57.0	57.1	



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# **Test description**

### **Conditions:**

- Frequency: 81.802971 MHz

- VDD: 2.5 V, 3.3 V

- Pull range: ±50 ppm, ±100 ppm, ±150 ppm, ±200 ppm, ±400 ppm

- Temperature: 25 °C

# **Equipment:**

Model	Measurement / Purpose
Keysight DSA90604A (6 GHz,	Period jitter, output amplitude, rise/fall time,
20 Gsps)	duty cycle
Keysight 5052B Signal Source	Phase noise, integrated phase jitter
Analyzer	
Keysight 34980A	Power supply current
Keysight E3631A	Power supply
Keysight 53230A	Frequency



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#### Setup

#### Waveform

For waveform parameters measurement (rise/fall time, differential swing, duty cycle), both DUT outputs are terminated with 30  $\Omega$  series and 50  $\Omega$  to GND. Output signals are measured using Keysight 1134B active probe with Keysight N5425B probe head. All measurements are applied to the differential waveform. Figure 6 shows test setup diagram for waveform parameters measurement.

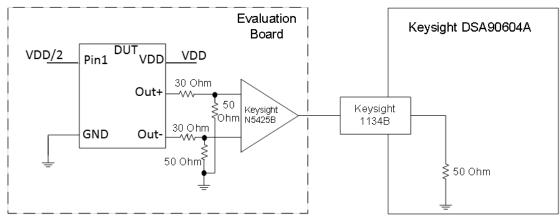


Figure 6. Test setup for measuring waveform parameters (rise/fall time, differential swing, duty cycle)

### **Period Jitter**

For period jitter measurement output is terminated with 30  $\Omega$  series and 50  $\Omega$  to GND at the input of hi-speed comparator (ADCMP581). AC coupled comparator's output is connected to oscilloscope channel. Figure 7 shows test setup diagram for period jitter measurement.

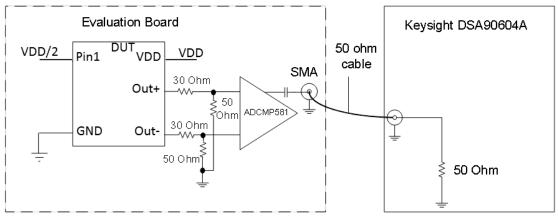


Figure 7. Test setup for measuring period jitter

<b>Si</b> Time	Title:	Performance report for SiT3372, 81.802971 MHz, HCSL		
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#### Phase noise

For phase noise measurements, differential signal is converted to single-ended using impedance matching transformer. Transformer's output is connected to measurement instrument. Output is also terminated with 30  $\Omega$  series at the source side. Figure 8 shows test setup diagram for phase noise measurement.

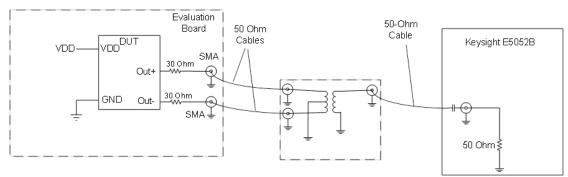


Figure 8. Test setup for measuring phase noise.

#### **Current consumption**

For Current consumption measurement device output is floating. For frequency measurement differential-to-single-ended converter is used.